

CHINA RRAM SUZHOU 2017



The *China RRAM International Workshop* launches its first edition on June 12th-14th of 2017 at Soochow University, with the objective of becoming the major forum for discussion on resistive random access memories and related applications in China. Topics of interest include: ReRAM, CBRAM, PCRAM, 2D materials in RRAM, *in-situ* characterization methods, and RRAM based neuromorphic computing.

Technical committee

- Mario Lanza, chair (Soochow University, China)
- Shibing Long (IMECAS, China)
- Qi Liu (IMECAS, China)
- Raghavan Nagarajan (SUTD, Singapore)

Confirmed invited speakers

- H.-S. Philip Wong (Stanford University, USA)
- Ming Liu (IMECAS, China)
- Paul C. McIntyre (Stanford University, USA)
- Huaqiang Wu (Tsinghua University, China)
- Ilia Valov (Forschungszentrum Juelich, Germany)
- Deji Akinwande (University of Texas, USA)
- Kin Leong Pey (SUTD, Singapore)
- Runwei Li (CNITECH, China)
- Hyunsang Hwang (POSTECH, Korea)
- Anthony Kenyon (University College London, UK)
- Luca Larcher (UNIMORE, Italy)
- Jordi Suñe (UAB, Catalonia, Spain)

Directions & Schedule

Updated information about accommodation and schedule will be available at the web www.ChinaRRAM.org

Call for Abstracts

Participants interested in presenting their work may send one-page abstract (with a figure) via Email by April 15th to the address: marco@suda.edu.cn

Social & Networking

Coffee breaks, social dinner and an excursion to a water town will be organized

The registration fee for the workshop is 1000 CNY and it must be completed on-site at the time of the conference. Selected works will be published as a special issue in *Crystal Research & Technology*. Dr. Hakim Meskine will discuss different publishing opportunities for the RRAM community in Wiley-VCH journals.



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More updated info at: www.ChinaRRAM.org

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